


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517214	<b>Applicant(s)/Patent Under Reexamination</b>  MAEKAWA ET AL.
	<b>Examiner</b>  Jaisle, Cecilia M	<b>Art Unit</b>  1624

SEARCHED			
Class	Subclass	Date	Examiner
514	403, 404	9/10/2008	Cecilia Jaisle
548	373.1, 375.1	9/10/2008	Cecilia Jaisle
546	275.4, 276.4	9/10/2008	C. Jaisle
544	238		

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	403, 404	9/10/2008	C. Jaisle
548	373.1, 375.1	9/10/2008	C. Jaisle

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